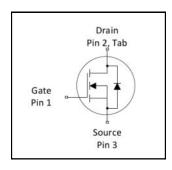
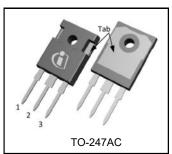
IRFP4868PbF



V _{DSS}	300V
R _{DS(on)} typ.	25.5m Ω
max.	32m Ω
I _D	70A





Applications

- High Efficiency Synchronous Rectification in SMPS
- Uninterruptible Power Supply
- High Speed Power Switching
- Hard Switched and High Frequency Circuits

Benefits

- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche SOA
- Enhanced body diode dV/dt and dI/dt Capability
- Lead-Free

Base Part Number	Package Type	Standard	Orderable Part Number	
		Form	Quantity	
IRFP4868PbF	TO-247AC	Tube	25	IRFP4868PbF

Absolute Maximum Ratings

Symbol	Parameter	Max.	Units
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V _{GS} @ 10V	70	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	49	Α
I _{DM}	Pulsed Drain Current ①	280	
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	517	W
	Linear Derating Factor	3.4	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
T_J	Operating Junction and	EE to 1.47E	
T _{STG} Storage Temperature Range		-55 to + 175	°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	
	Mounting torque, 6-32 or M3 screw	10lbf-in (1.1N-m)	

Avalanche Characteristics

E _{AS} (Thermally limited)	Single Pulse Avalanche Energy ②	1093	mJ
I _{AR}	Avalanche Current ①	Soo Fig. 14, 15, 22a, 22b	Α
E _{AR}	Repetitive Avalanche Energy ①	See Fig. 14, 15, 22a, 22b	mJ

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case ⑦⑧		0.29	
$R_{\theta CS}$	Case-to-Sink, Flat Greased Surface	0.24		°C/W
$R_{\theta JA}$	Junction-to-Ambient		40	



Static @ T_J = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
	Drain-to-Source Breakdown Voltage	300			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.29		V/°C	Reference to 25°C, I _D = 5mA①
R _{DS(on)}	Static Drain-to-Source On-Resistance		25.5	32	mΩ	V _{GS} = 10V, I _D = 42A ④
$V_{GS(th)}$	Gate Threshold Voltage	3.0		5.0	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
	Drain-to-Source Leakage Current			20		$V_{DS} = 300V, V_{GS} = 0V$
I _{DSS}	Drain-to-Source Leakage Current			250	μΑ	$V_{DS} = 300V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
	Gate-to-Source Forward Leakage			100	nΛ	$V_{GS} = 20V$
I _{GSS}	Gate-to-Source Reverse Leakage			-100	nA	$V_{GS} = -20V$
R_G	Internal Gate Resistance		1.1		Ω	

Dynamic @ T_J = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
gfs	Forward Transconductance	80			S	$V_{DS} = 50V, I_{D} = 42A$
Q_g	Total Gate Charge		180	270		I _D = 42A
Q_{gs}	Gate-to-Source Charge		60		nC	V _{DS} =150V
Q_{gd}	Gate-to-Drain ("Miller") Charge		57		IIC	V _{GS} = 10V ④
Q _{sync}	Total Gate Charge Sync. (Q _g - Q _{gd})		123			$I_D = 42A, V_{DS} = 0V, V_{GS} = 10V$
t _{d(on)}	Turn-On Delay Time		24			V _{DD} = 195V
t _r	Rise Time		50]	I _D = 42A
$t_{d(off)}$	Turn-Off Delay Time		62		ns	$R_G = 1.0\Omega$
t _f	Fall Time		45			V _{GS} = 10V ④
C _{iss}	Input Capacitance		10774			$V_{GS} = 0V$
Coss	Output Capacitance		612			$V_{DS} = 50V$
C_{rss}	Reverse Transfer Capacitance		193			f = 1.0 MHz, See Fig. 5
C _{oss} eff. (ER)	Effective Output Capacitance		406			$V_{GS} = 0V$, $V_{DS} = 0V$ to 240V ©,
	(Energy Related) ©		400			See Fig. 11
C _{oss} eff. (TR)	Effective Output Capacitance (Time Related)®		710			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 240V $

Diode Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			70	Α	MOSFET symbol
	(Body Diode)			70	^	showing the
I _{SM}	Pulsed Source Current			280	Α	integral reverse
	(Body Diode) ①			200	^	p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$, $I_S = 42A$, $V_{GS} = 0V$ ④
dv/dt	Peak Diode Recovery ③		7.3		V/ns	$T_J = 25$ °C, $I_S = 42A$, $V_{DS} = 300V$
t _{rr}	Reverse Recovery Time		351		no	$T_J = 25^{\circ}C$
			454		ns	$T_J = 125^{\circ}C$ $V_R = 255V$,
Q _{rr}	Reverse Recovery Charge		2520		nC	$T_J = 25^{\circ}C$ $I_F = 42A$ $di/dt = 100A/\mu s$ $\textcircled{4}$
			3686			T _J = 125°C
I _{RRM}	Reverse Recovery Current		16		Α	T _J = 25°C
t _{on}				on time	e is ne	gligible (turn-on is dominated by
		L _S +L _D)			

Notes:

- ① Repetitive rating; pulse width limited by max. Junction temperature.
- ② Limited by T_{Jmax} , starting $T_J = 25^{\circ}C$, L = 1.2mH $R_G = 50\Omega$, $I_{AS} = 42A$, $V_{GS} = 10V$. Part not recommended for use above this value.
- ③ $I_{SD} \le 42A$, di/dt ≤ 1706A/ μ s, $V_{DD} \le V_{(BR)DSS}$, $T_{J} \le 175$ °C.
- ④ Pulse width ≤ 400µs; duty cycle ≤ 2%.

- © Coss eff. (ER) is a fixed capacitance that gives the same energy as Coss while V_{DS} is rising from 0 to 80% V_{DSS} .
- $\ensuremath{\mathfrak{D}}$ R_{θ} is measured at T_J approximately 90°C.
- $\$ $R_{\theta JC}$ value shown is at time zero.

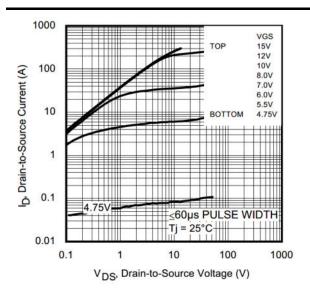


Fig 1. Typical Output Characteristics

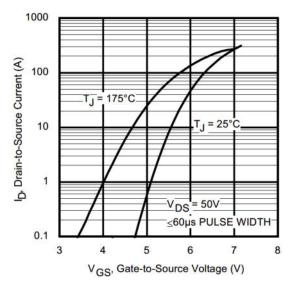


Fig 3. Typical Transfer Characteristics

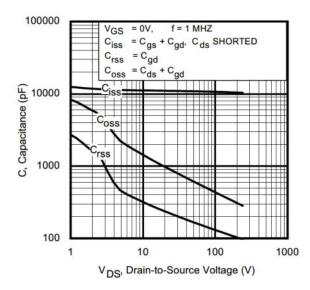


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

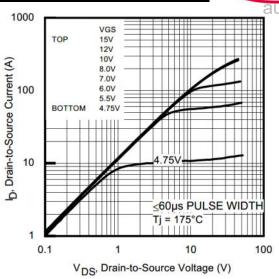


Fig 2. Typical Output Characteristics

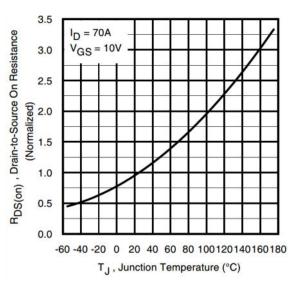


Fig 4. Normalized On-Resistance vs. Temperature

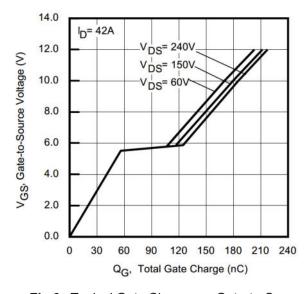


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage



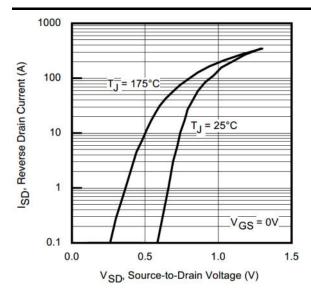


Fig 7. Typical Source-to-Drain Diode Forward Voltage

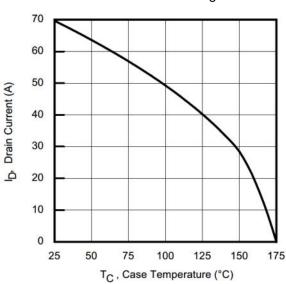


Fig 9. Maximum Drain Current vs. Case Temperature

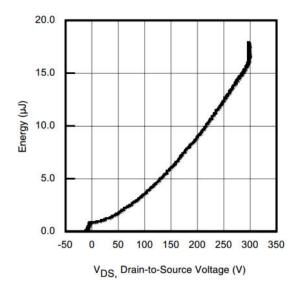


Fig 11. Typical Coss Stored Energy

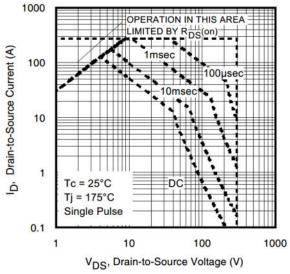


Fig 8. Maximum Safe Operating Area

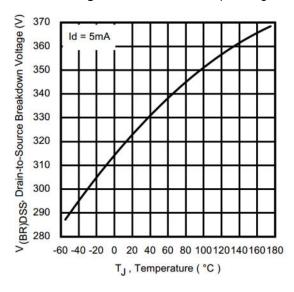


Fig 10. Drain-to-Source Breakdown Voltage

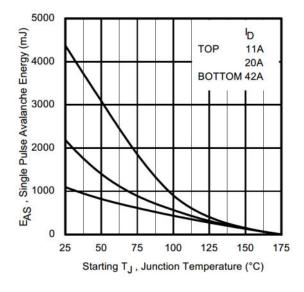


Fig 12. Maximum Avalanche Energy vs. Drain Current



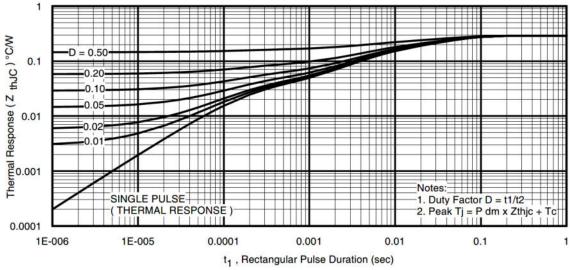


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

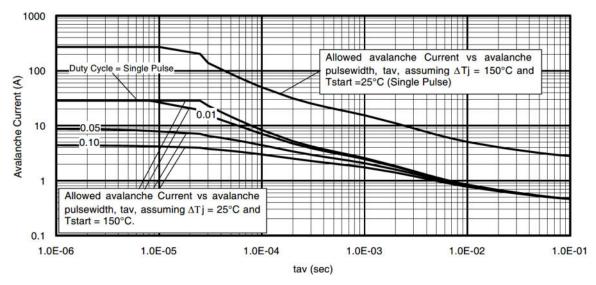


Fig 14. Typical Avalanche Current vs. Pulsewidth

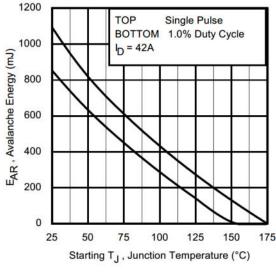


Fig 15. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves, Figures 14, 15: (For further info, see AN-1005 at www.irf.com)

1. Avalanche failures assumption:

Purely a thermal phenomenon and failure occurs at a temperature far in excess of Timax. This is validated for every part type.

2. Safe operation in Avalanche is allowed as long as Tjmax is not exceeded.

3. Equation below based on circuit and waveforms shown in Figures 16a, 16b.

4. P_{D (ave)} = Average power dissipation per single avalanche pulse.

5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).

6. I_{av} = Allowable avalanche current.

7. ΔT = Allowable rise in junction temperature, not to exceed Timax (assumed as 25°C in Figure 14, 15). t_{av} = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

 $Z_{th,JC}(D, t_{av})$ = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; \left(\; 1.3 \cdot BV \cdot I_{av} \right) = \Delta T / \; Z_{thJC} \\ I_{av} &= 2\Delta T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$



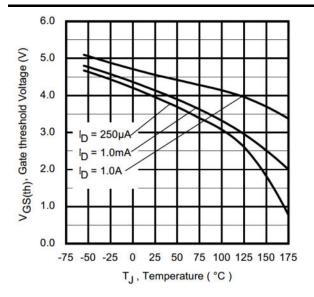


Fig. 16 Threshold Voltage vs. Temperature

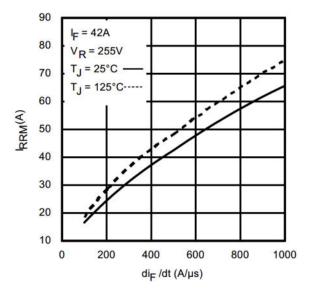


Fig 18. Typical Recovery Current vs. di_f/dt

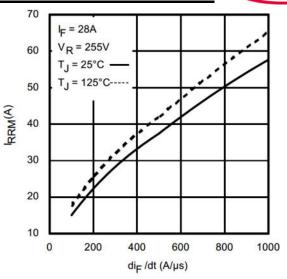


Fig. 17 Typical Recovery Current vs. di_f/dt

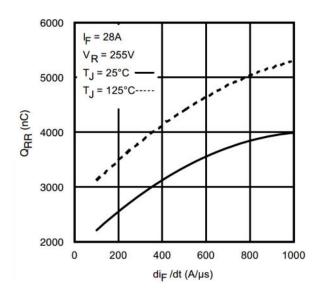


Fig 19. Typical Stored Charge vs. di_f/dt

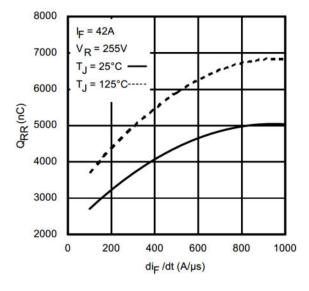
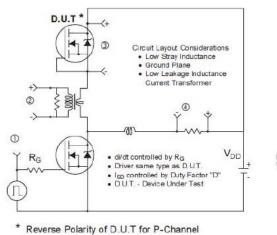


Fig 20. Typical Stored Charge vs. di_f/dt





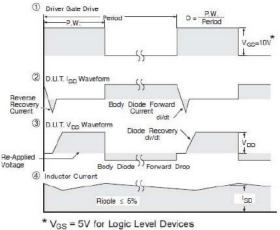


Fig 21. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

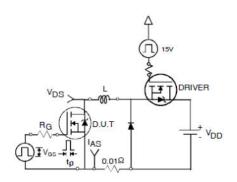


Fig 22a. Unclamped Inductive Test Circuit

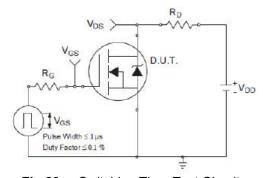


Fig 23a. Switching Time Test Circuit

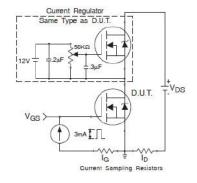


Fig 24a. Gate Charge Test Circuit

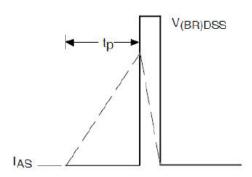


Fig 22b. Unclamped Inductive Waveforms

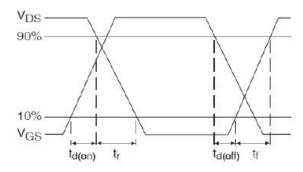


Fig 23b. Switching Time Waveforms

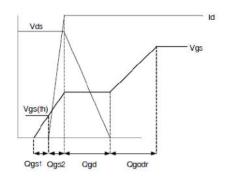
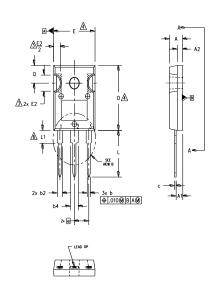
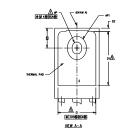


Fig 24b. Gate Charge Waveform

infineon

TO-247AC Package Outline (Dimensions are









TO-247AC Part Marking Information

NOTES:

1. DIMENSIONING AND TOLERANCING AS PER ASME Y14.5M 1994.

2. DIMENSIONS ARE SHOWN IN INCHES.

CONTOUR OF SLOT OPTIONAL.

\(\) DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127)
PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

5. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS D1 & E1.

LEAD FINISH UNCONTROLLED IN L1.

OP TO HAVE A MAXIMUM DRAFT ANGLE OF 1.5 'TO THE TOP OF THE PART WITH A MAXIMUM HOLE DIAMETER OF .154 INCH.

8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-247AC .

	DIMENSIONS					
SYMBOL	INC	HES	MILLIM	ETERS		
	MIN.	MAX.	MIN.	MAX.	NOTES	
Α	.183	.209	4.65	5.31		
A1	.087	.102	2.21	2.59		
A2	.059	.098	1.50	2.49		
b	.039	.055	0.99	1.40		
ь1	.039	.053	0.99	1.35		
b2	.065	.094	1.65	2.39		
b3	.065	.092	1.65	2.34		
b4	.102	.135	2.59	3.43		
b5	.102	.133	2.59	3.38		
С	.015	.035	0.38	0.89		
c1	.015	.033	0.38	0.84		
D	.776	.815	19.71	20.70	4	
D1	.515	-	13.08	-	5	
D2	.020	.053	0.51	1.35		
Ε	.602	.625	15.29	15.87	4	
E1	.530	-	13.46	_		
E2	.178	.216	4.52	5.49		
е	.215	BSC	5.46	BSC		
Øk	.0	10	0.	25		
L	.559	.634	14.20	16.10		
L1	.146	.169	3.71	4.29		
øΡ	.140	.144	3.56	3.66		
øP1	-	.291	-	7.39		
Q	.209	.224	5.31	5.69		
S	.217	BSC	5.51	BSC		
			ı			

LEAD ASSIGNMENTS

<u>HEXFET</u>

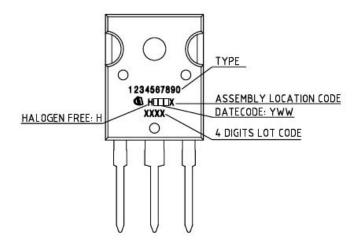
- 1.- GATE
- 2.- DRAIN 3.- SOURCE
- 4.- DRAIN

IGBTs, CoPACK

- 1.- GATE
- 2.- COLLECTOR 3.- EMITTER
- 4.- COLLECTOR

DIODES

- 1.- ANODE/OPEN
- 2.- CATHODE
- 3.- ANODE



TO-247AC package is not recommended for Surface Mount Application.



Qualification information

	Industrial				
Qualification level	(per JEDEC JESD47F) [†]				
Moisture Sensitivity Level	TO-247AC	N/A			
RoHS compliant	Yes				

[†] Applicable version of JEDEC standard at the time of product release.

Revision History

Date	Rev.	Comments
		Changed datasheet with Infineon logo-all pages
06/21/2017	2.1	Corrected Package outline on page 8.
		Added disclaimer on last page.
06/40/2024	2.2	Update datasheet to Infineon format
06/10/2024	2.2	Corrected trise to latest lab measurements
10/18/2024	2.3	Updated Part marking –page 8



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